

RF Power LDMOS Transistor

N-Channel Enhancement-Mode Lateral MOSFET

This 50 W RF power LDMOS transistor is designed for cellular base station applications covering the frequency range of 1805 to 1880 MHz.

1800 MHz

- Typical Single-Carrier W-CDMA Performance: $V_{DD} = 28$ Vdc, $I_{DQ} = 1400$ mA, $P_{out} = 50$ W Avg., Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF.

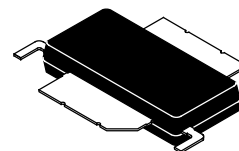
| Frequency | G_{ps} (dB) | η_D (%) | Output PAR (dB) | ACPR (dBc) | IRL (dB) |
|-----------|---------------|--------------|-----------------|------------|----------|
| 1805 MHz | 17.1 | 33.3 | 7.1 | -33.6 | -14 |
| 1840 MHz | 17.5 | 33.3 | 7.1 | -33.6 | -16 |
| 1880 MHz | 17.6 | 33.8 | 6.9 | -33.7 | -11 |

Features

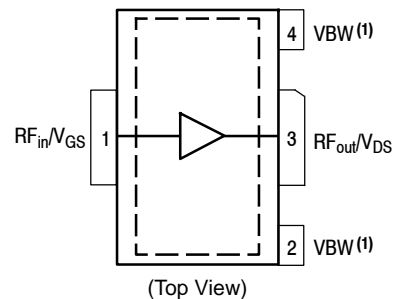
- High thermal conductivity packaging technology for reduced thermal resistance
- Greater negative gate-source voltage range for improved Class C operation
- Designed for digital predistortion error correction systems
- Optimized for Doherty applications

AFT18S230-12NR3

**1805-1880 MHz, 50 W AVG., 28 V
 AIRFAST RF POWER LDMOS
 TRANSISTOR**



**OM-780-2L2L
 PLASTIC**



Note: Exposed backside of the package is the source terminal for the transistor.

Figure 1. Pin Connections

1. Device cannot operate with the V_{DD} current supplied through pin 2 and pin 4.

Table 1. Maximum Ratings

| Rating | Symbol | Value | Unit |
|--|-----------|-------------|------|
| Drain-Source Voltage | V_{DSS} | -0.5, +65 | Vdc |
| Gate-Source Voltage | V_{GS} | -6.0, +10 | Vdc |
| Operating Voltage | V_{DD} | 32, +0 | Vdc |
| Storage Temperature Range | T_{stg} | -65 to +150 | °C |
| Case Operating Temperature Range | T_C | -40 to +150 | °C |
| Operating Junction Temperature Range (1,2) | T_J | -40 to +225 | °C |

Table 2. Thermal Characteristics

| Characteristic | Symbol | Value (2,3) | Unit |
|--|-----------------|-------------|------|
| Thermal Resistance, Junction to Case Case Temperature 78°C, 50 W CW, 28 Vdc, $I_{DQ} = 1400$ mA, 1842.5 MHz | $R_{\theta JC}$ | 0.27 | °C/W |

Table 3. ESD Protection Characteristics

| Test Methodology | Class |
|---------------------------------------|-------|
| Human Body Model (per JESD22-A114) | 2 |
| Machine Model (per EIA/JESD22-A115) | B |
| Charge Device Model (per JESD22-C101) | IV |

Table 4. Moisture Sensitivity Level

| Test Methodology | Rating | Package Peak Temperature | Unit |
|--------------------------------------|--------|--------------------------|------|
| Per JESD22-A113, IPC/JEDEC J-STD-020 | 3 | 260 | °C |

Table 5. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

| Characteristic | Symbol | Min | Typ | Max | Unit |
|----------------|--------|-----|-----|-----|------|
|----------------|--------|-----|-----|-----|------|

Off Characteristics

| | | | | | |
|---|-----------|---|---|----|-----------------|
| Zero Gate Voltage Drain Leakage Current ($V_{DS} = 65$ Vdc, $V_{GS} = 0$ Vdc) | I_{DSS} | — | — | 10 | μAdc |
| Zero Gate Voltage Drain Leakage Current ($V_{DS} = 28$ Vdc, $V_{GS} = 0$ Vdc) | I_{DSS} | — | — | 1 | μAdc |
| Gate-Source Leakage Current ($V_{GS} = 5$ Vdc, $V_{DS} = 0$ Vdc) | I_{GSS} | — | — | 1 | μAdc |

On Characteristics

| | | | | | |
|--|--------------|-----|------|-----|-----|
| Gate Threshold Voltage ($V_{DS} = 10$ Vdc, $I_D = 291$ μAdc) | $V_{GS(th)}$ | 1.0 | 2.0 | 2.5 | Vdc |
| Gate Quiescent Voltage ($V_{DD} = 28$ Vdc, $I_D = 1400$ mAdc, Measured in Functional Test) | $V_{GS(Q)}$ | 2.3 | 2.8 | 3.3 | Vdc |
| Drain-Source On-Voltage ($V_{GS} = 10$ Vdc, $I_D = 2.9$ Adc) | $V_{DS(on)}$ | 0.1 | 0.24 | 0.3 | Vdc |

Functional Tests (4) (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 28$ Vdc, $I_{DQ} = 1400$ mA, $P_{out} = 50$ W Avg., $f = 1880$ MHz, Single-Carrier W-CDMA, IQ Magnitude Clipping, Input Signal PAR = 9.9 dB @ 0.01% Probability on CCDF. ACPR measured in 3.84 MHz Channel Bandwidth @ ± 5 MHz Offset.

| | | | | | |
|--|----------|------|-------|-------|-----|
| Power Gain | G_{ps} | 16.3 | 17.6 | 19.3 | dB |
| Drain Efficiency | η_D | 29.0 | 33.8 | — | % |
| Output Peak-to-Average Ratio @ 0.01% Probability on CCDF | PAR | 6.0 | 6.9 | — | dB |
| Adjacent Channel Power Ratio | ACPR | — | -33.7 | -30.0 | dBc |
| Input Return Loss | IRL | — | -11 | -6 | dB |

1. Continuous use at maximum temperature will affect MTTF.
2. MTTF calculator available at <http://www.freescale.com/rf/calculators>.
3. Refer to [AN1955](#), *Thermal Measurement Methodology of RF Power Amplifiers*. Go to <http://www.freescale.com/rf> and search for AN1955.
4. Part internally matched both on input and output.

(continued)

Table 5. Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted) (continued)

| Characteristic | Symbol | Min | Typ | Max | Unit |
|--|-----------------------|-----|-------|-----|-------|
| Load Mismatch (In Freescale Test Fixture, 50 ohm system) $I_{DQ} = 1400\text{ mA}$, $f = 1840\text{ MHz}$ | | | | | |
| VSWR 10:1 at 32 Vdc, 309 W CW Output Power (3 dB Input Overdrive from 204 W CW Rated Power) | No Device Degradation | | | | |
| Typical Performance (In Freescale Test Fixture, 50 ohm system) $V_{DD} = 28\text{ Vdc}$, $I_{DQ} = 1400\text{ mA}$, 1805–1880 MHz Bandwidth | | | | | |
| P_{out} @ 1 dB Compression Point, CW | P1dB | — | 204 | — | W |
| AM/PM (Maximum value measured at the P3dB compression point across the 1805–1880 MHz bandwidth) | Φ | — | -17 | — | ° |
| VBW Resonance Point (IMD Third Order Intermodulation Inflection Point) | VBW _{res} | — | 70 | — | MHz |
| Gain Flatness in 75 MHz Bandwidth @ $P_{out} = 50\text{ W Avg.}$ | G_F | — | 0.4 | — | dB |
| Gain Variation over Temperature (-30°C to +85°C) | ΔG | — | 0.009 | — | dB/°C |
| Output Power Variation over Temperature (-30°C to +85°C) | $\Delta P1dB$ | — | 0.006 | — | dB/°C |

Table 6. Ordering Information

| Device | Tape and Reel Information | Package |
|-----------------|---|-------------|
| AFT18S230-12NR3 | R3 Suffix = 250 Units, 32 mm Tape Width, 13-inch Reel | OM-780-2L2L |

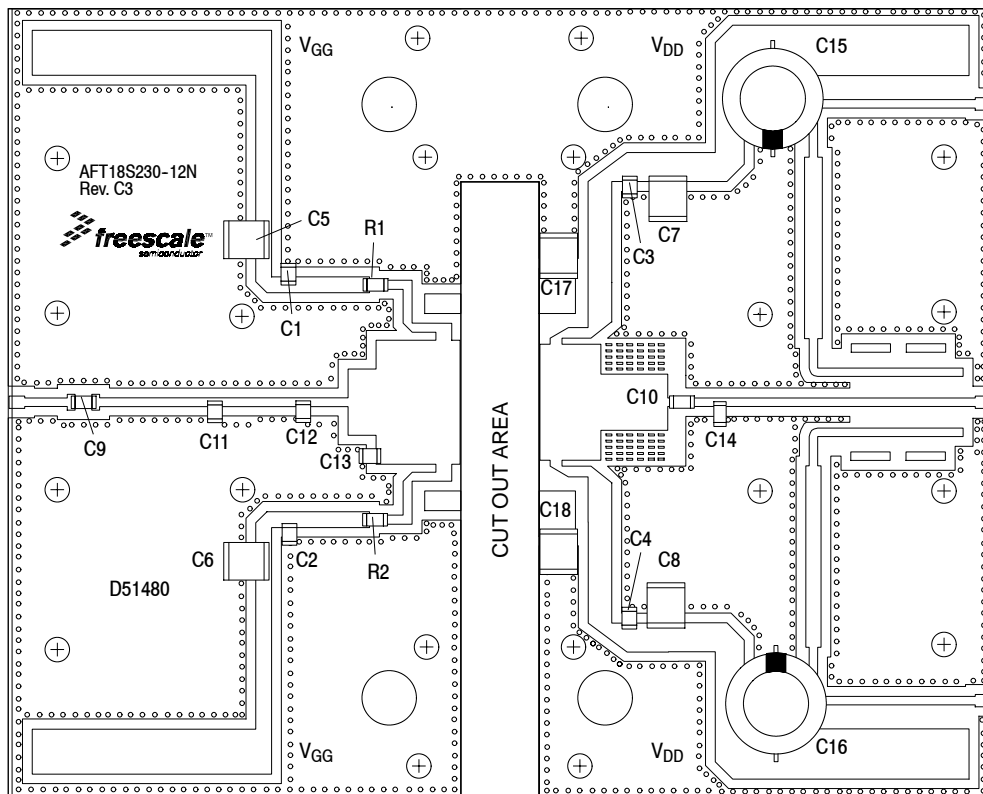


Figure 2. AFT18S230-12NR3 Test Circuit Component Layout

Table 7. AFT18S230-12NR3 Test Circuit Component Designations and Values

| Part | Description | Part Number | Manufacturer |
|--------------------------|---|---------------------|--------------------|
| C1, C2, C3, C4, C9 | 12 pF Chip Capacitors | ATC100B120FW1500XT | ATC |
| C5, C6, C7, C8, C17, C18 | 10 μ F Chip Capacitors | C5750X7S2A106M230KB | TDK |
| C10 | 6.8 pF Chip Capacitor | ATC100B6R8BW1500XT | ATC |
| C11 | 1.1 pF Chip Capacitor | ATC100B1R1BW1500XT | ATC |
| C12 | 1.0 pF Chip Capacitor | ATC100B1R0BW1500XT | ATC |
| C13 | 0.4 pF Chip Capacitor | ATC100B0R4BW1500XT | ATC |
| C14 | 0.9 pF Chip Capacitor | ATC100B0R9BW1500XT | ATC |
| C15, C16 | 470 μ F, 50 V Electrolytic Capacitors | 477CKS050M | Illinois Capacitor |
| R1, R2 | 4.02 Ω , 1/4 W Chip Resistors | CRCW12064R02FKEA | Vishay |
| PCB | Rogers RO4350B, 0.020", $\epsilon_r = 3.66$ | D51480 | MTL |

TYPICAL CHARACTERISTICS

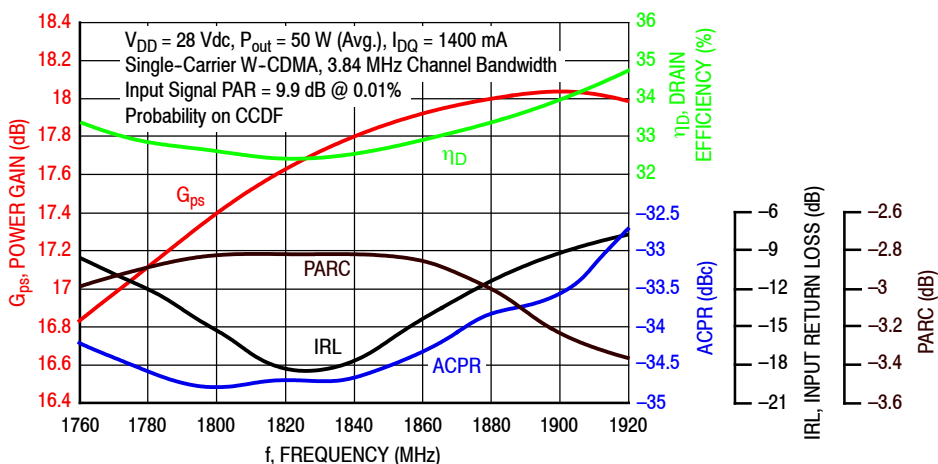


Figure 3. Single-Carrier Output Peak-to-Average Ratio Compression (PARC) Broadband Performance @ $P_{out} = 50$ Watts Avg.

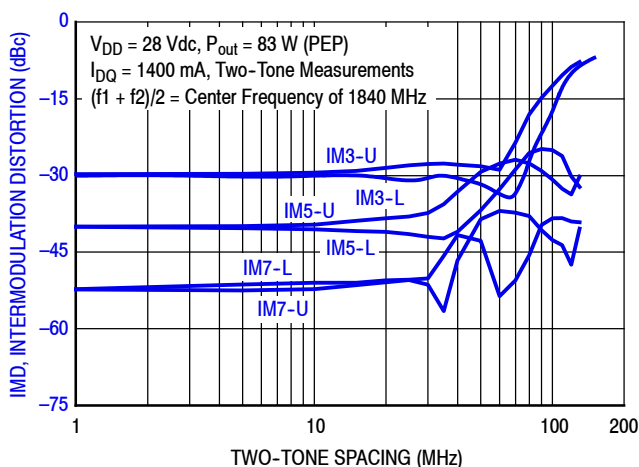


Figure 4. Intermodulation Distortion Products versus Two-Tone Spacing

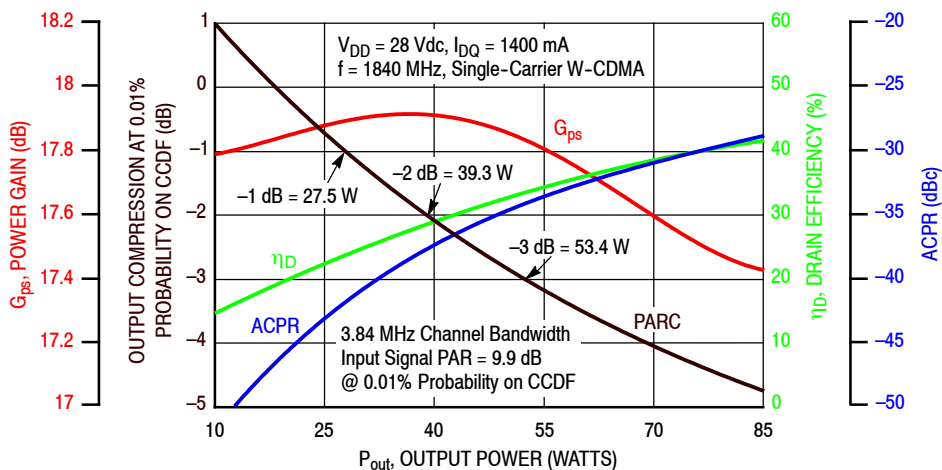


Figure 5. Output Peak-to-Average Ratio Compression (PARC) versus Output Power

TYPICAL CHARACTERISTICS

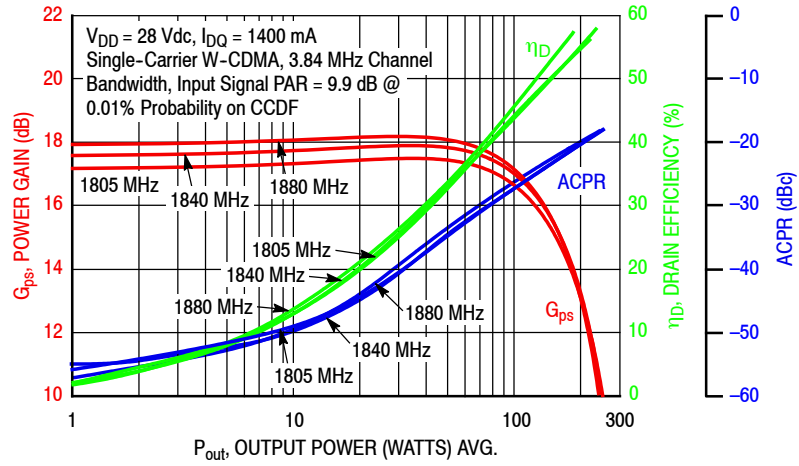


Figure 6. Single-Carrier W-CDMA Power Gain, Drain Efficiency and ACPR versus Output Power

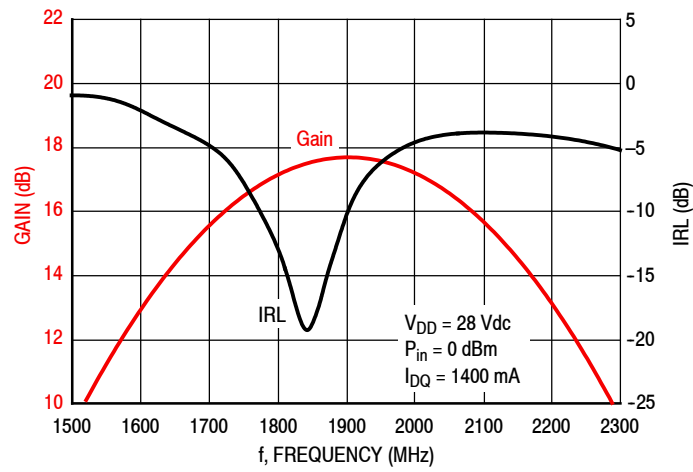


Figure 7. Broadband Frequency Response

Table 8. Load Pull Performance — Maximum Power Tuning
 $V_{DD} = 28 \text{ Vdc}$, $I_{DQA} = 1400 \text{ mA}$, Pulsed CW, $10 \mu\text{sec(ON)}$, 10% Duty Cycle

| f (MHz) | $Z_{\text{source}} (\Omega)$ | $Z_{\text{in}} (\Omega)$ | Max Output Power | | | | | |
|---------|------------------------------|--------------------------|----------------------------------|-----------|-------|-----|--------------|-----------|
| | | | P1dB | | | | | |
| | | | $Z_{\text{load}}^{(1)} (\Omega)$ | Gain (dB) | (dBm) | (W) | η_D (%) | AM/PM (°) |
| 1805 | $1.17 - j4.25$ | $1.10 + j3.92$ | $1.10 - j3.55$ | 16.8 | 54.0 | 250 | 53.4 | -12 |
| 1840 | $1.69 - j4.78$ | $1.38 + j4.25$ | $1.06 - j3.65$ | 16.7 | 54.0 | 253 | 53.5 | -13 |
| 1880 | $3.16 - j5.35$ | $2.16 + j4.57$ | $1.09 - j3.92$ | 16.5 | 54.0 | 250 | 52.4 | -13 |

| f (MHz) | $Z_{\text{source}} (\Omega)$ | $Z_{\text{in}} (\Omega)$ | Max Output Power | | | | | |
|---------|------------------------------|--------------------------|----------------------------------|-----------|-------|-----|--------------|-----------|
| | | | P3dB | | | | | |
| | | | $Z_{\text{load}}^{(2)} (\Omega)$ | Gain (dB) | (dBm) | (W) | η_D (%) | AM/PM (°) |
| 1805 | $1.17 - j4.25$ | $1.07 + j4.03$ | $1.10 - j3.61$ | 14.7 | 54.7 | 298 | 55.8 | -18 |
| 1840 | $1.69 - j4.78$ | $1.39 + j4.39$ | $1.13 - j3.80$ | 14.6 | 54.8 | 299 | 56.1 | -18 |
| 1880 | $3.16 - j5.35$ | $2.25 + j4.78$ | $1.16 - j4.07$ | 14.3 | 54.7 | 296 | 54.3 | -18 |

(1) Load impedance for optimum P1dB power.

(2) Load impedance for optimum P3dB power.

 Z_{source} = Measured impedance presented to the input of the device at the package reference plane.

 Z_{in} = Impedance as measured from gate contact to ground.

 Z_{load} = Measured impedance presented to the output of the device at the package reference plane.

Table 9. Load Pull Performance — Maximum Drain Efficiency Tuning
 $V_{DD} = 28 \text{ Vdc}$, $I_{DQA} = 1400 \text{ mA}$, Pulsed CW, $10 \mu\text{sec(ON)}$, 10% Duty Cycle

| f (MHz) | $Z_{\text{source}} (\Omega)$ | $Z_{\text{in}} (\Omega)$ | Max Drain Efficiency | | | | | |
|---------|------------------------------|--------------------------|----------------------------------|-----------|-------|-----|--------------|-----------|
| | | | P1dB | | | | | |
| | | | $Z_{\text{load}}^{(1)} (\Omega)$ | Gain (dB) | (dBm) | (W) | η_D (%) | AM/PM (°) |
| 1805 | $1.17 - j4.25$ | $1.12 + j4.11$ | $1.95 - j2.42$ | 19.5 | 52.3 | 171 | 64.8 | -19 |
| 1840 | $1.69 - j4.78$ | $1.48 + j4.43$ | $1.88 - j2.54$ | 19.3 | 52.2 | 168 | 64.6 | -20 |
| 1880 | $3.16 - j5.35$ | $2.41 + j4.75$ | $1.77 - j2.67$ | 19.1 | 52.2 | 164 | 64.1 | -20 |

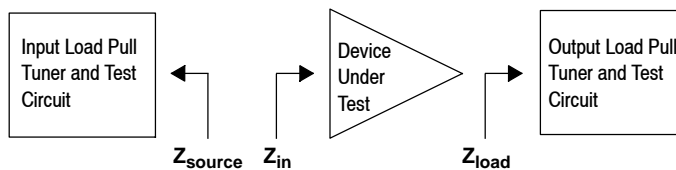
| f (MHz) | $Z_{\text{source}} (\Omega)$ | $Z_{\text{in}} (\Omega)$ | Max Drain Efficiency | | | | | |
|---------|------------------------------|--------------------------|----------------------------------|-----------|-------|-----|--------------|-----------|
| | | | P3dB | | | | | |
| | | | $Z_{\text{load}}^{(2)} (\Omega)$ | Gain (dB) | (dBm) | (W) | η_D (%) | AM/PM (°) |
| 1805 | $1.17 - j4.25$ | $1.08 + j4.14$ | $1.80 - j2.54$ | 17.3 | 53.2 | 211 | 67.0 | -26 |
| 1840 | $1.69 - j4.78$ | $1.42 + j4.52$ | $1.69 - j2.54$ | 17.3 | 52.9 | 197 | 66.5 | -28 |
| 1880 | $3.16 - j5.35$ | $2.40 + j4.89$ | $1.73 - j2.72$ | 17.1 | 52.9 | 193 | 65.4 | -26 |

(1) Load impedance for optimum P1dB efficiency.

(2) Load impedance for optimum P3dB efficiency.

 Z_{source} = Measured impedance presented to the input of the device at the package reference plane.

 Z_{in} = Impedance as measured from gate contact to ground.

 Z_{load} = Measured impedance presented to the output of the device at the package reference plane.


P1dB – TYPICAL LOAD PULL CONTOURS — 1840 MHz

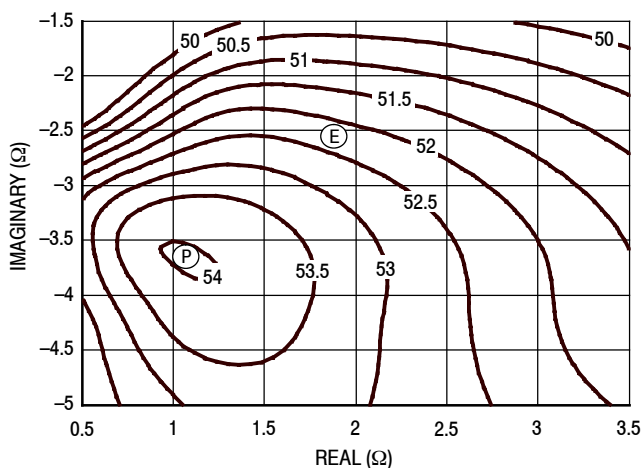


Figure 8. P1dB Load Pull Output Power Contours (dBm)

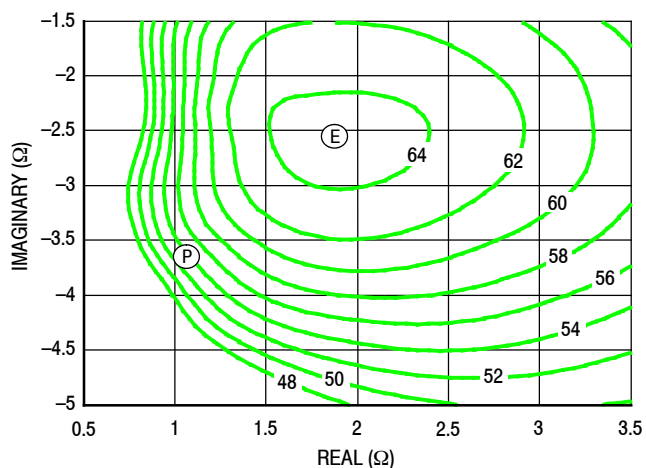


Figure 9. P1dB Load Pull Efficiency Contours (%)

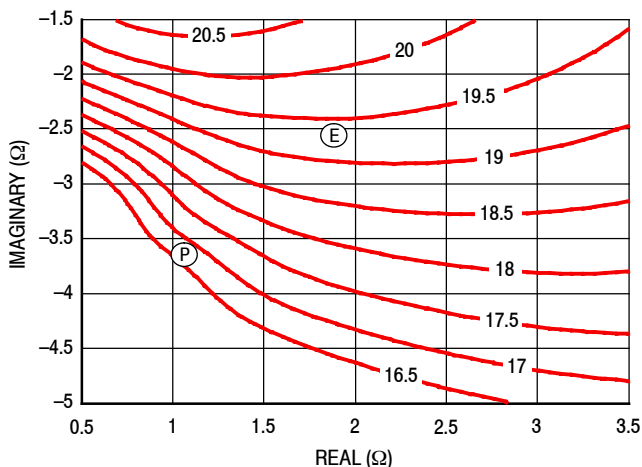


Figure 10. P1dB Load Pull Gain Contours (dB)

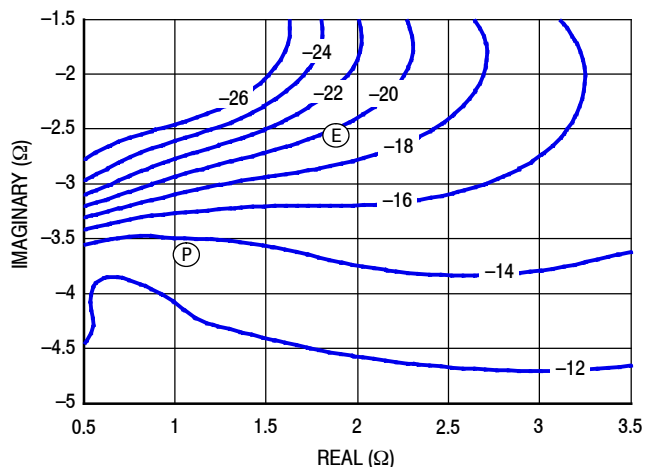


Figure 11. P1dB Load Pull AM/PM Contours (°)

NOTE: (P) = Maximum Output Power
(E) = Maximum Drain Efficiency

- Gain
- Drain Efficiency
- Linearity
- Output Power

P3dB – TYPICAL LOAD PULL CONTOURS — 1840 MHz

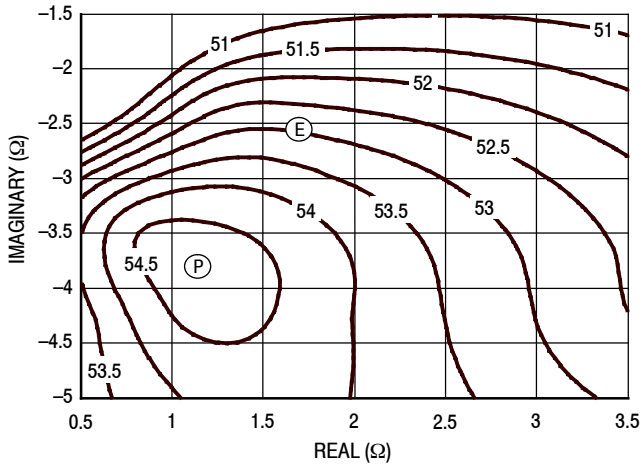


Figure 12. P3dB Load Pull Output Power Contours (dBm)

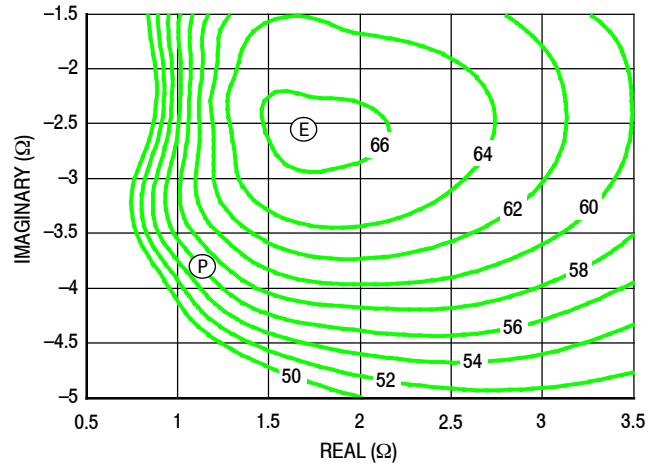


Figure 13. P3dB Load Pull Efficiency Contours (%)

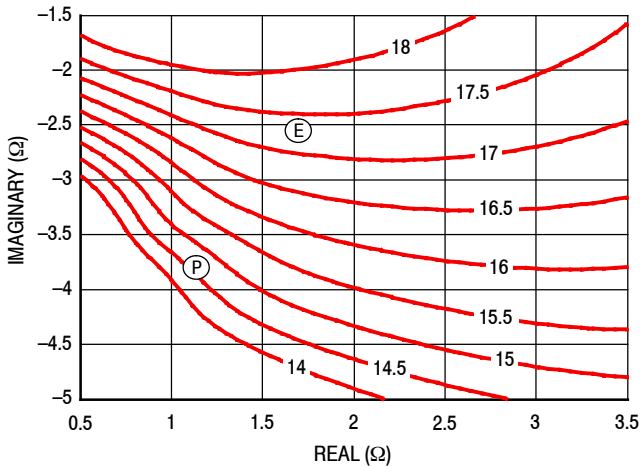


Figure 14. P3dB Load Pull Gain Contours (dB)

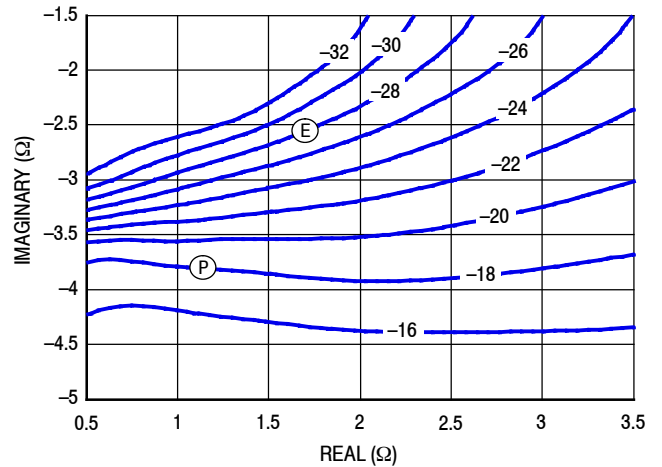
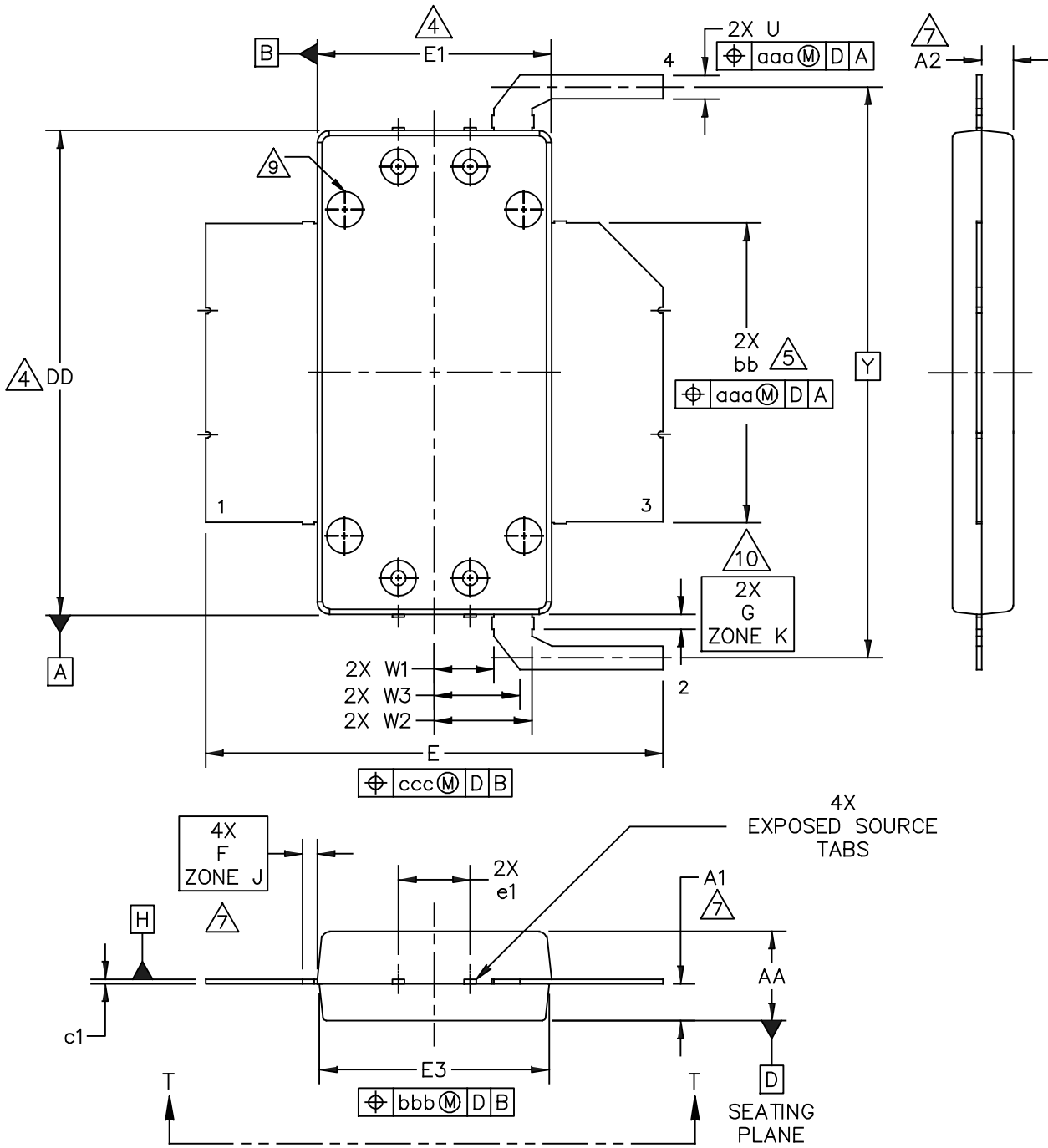


Figure 15. P3dB Load Pull AM/PM Contours (°)

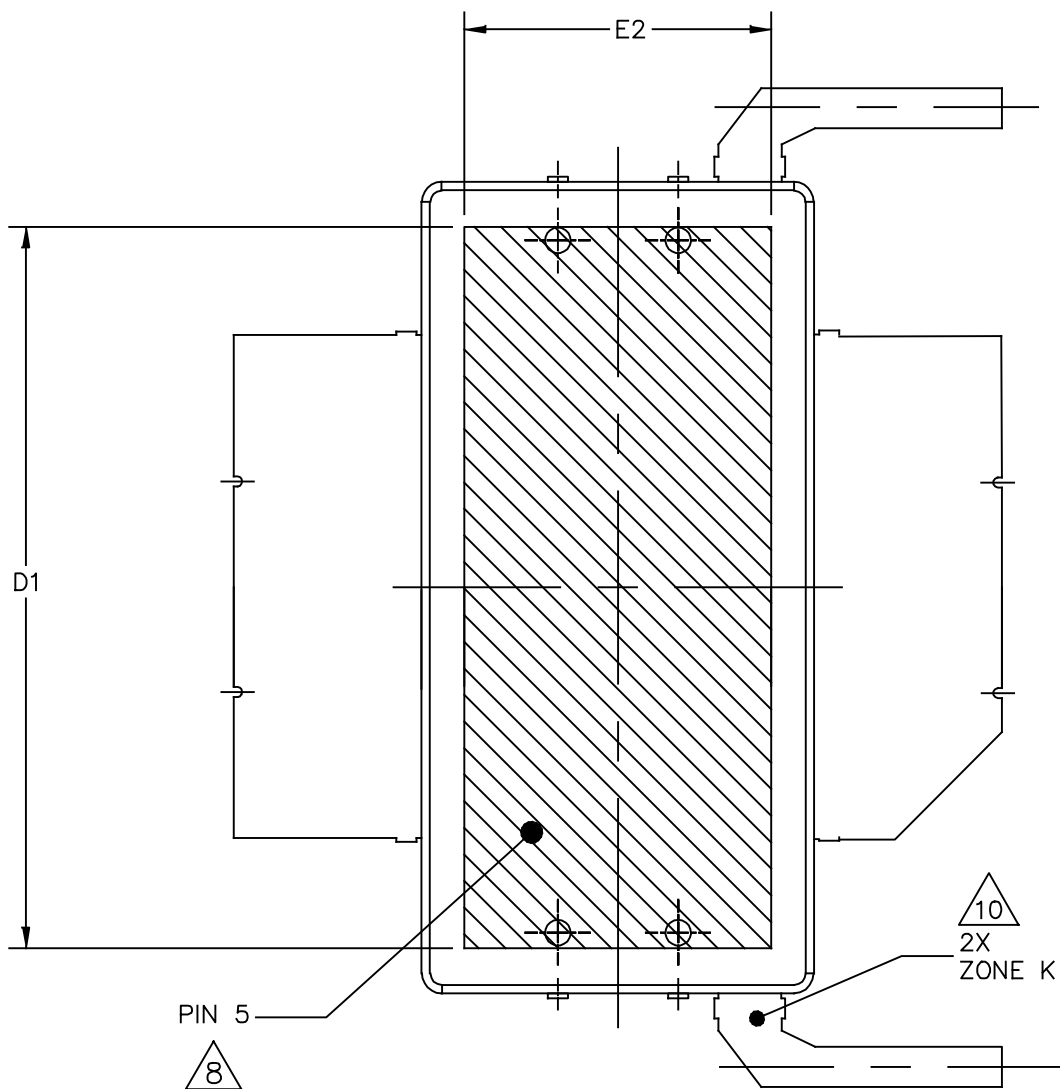
NOTE: (P) = Maximum Output Power
(E) = Maximum Drain Efficiency

- Gain
- Drain Efficiency
- Linearity
- Output Power

PACKAGE DIMENSIONS



| | | |
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BOTTOM VIEW
VIEW T-T

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NOTES:

1. CONTROLLING DIMENSION: INCH
2. INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M-1994.
3. DATUM PLANE H IS LOCATED AT TOP OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE TOP OF THE PARTING LINE.
4. DIMENSIONS DD AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS .006 INCH (0.15 MM) PER SIDE. DIMENSIONS DD AND E1 DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE H.
5. DIMENSION bb DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE .005 INCH (0.13 MM) TOTAL IN EXCESS OF THE bb DIMENSION AT MAXIMUM MATERIAL CONDITION.
6. DATUMS A AND B TO BE DETERMINED AT DATUM PLANE H.
7. DIMENSIONS A1 AND A2 APPLIES WITHIN ZONE J ONLY. A1 APPLIES TO PINS 1 AND 3. A2 APPLIES TO PINS 2 AND 4. TOLERANCES OF DIMENSIONS A1 AND A2 ARE TENTATIVE.
8. HATCHING REPRESENTS THE EXPOSED AREA OF THE HEAT SLUG. THE DIMENSIONS D1 AND E2 REPRESENT THE VALUES BETWEEN THE TWO OPPOSITE POINTS ALONG THE EDGES OF EXPOSED AREA OF HEAT SLUG.
9. DIMPLED HOLE REPRESENTS INPUT SIDE.
10. ZONE K REPRESENTS NON-SOLDERABLE REGION WHERE MOLD FLASH AND RESIN BLEED ARE PERMITTED ON BOTH SIDES OF THE LEADS.

| DIM | INCH | | MILLIMETER | | DIM | INCH | | MILLIMETER | |
|-----|----------|------|------------|-------|-----|----------|------|------------|-------|
| | MIN | MAX | MIN | MAX | | MIN | MAX | MIN | MAX |
| AA | .148 | .152 | 3.76 | 3.86 | W1 | .095 | .105 | 2.41 | 2.67 |
| A1 | .059 | .065 | 1.50 | 1.65 | W2 | .158 | .168 | 4.01 | 4.27 |
| A2 | .056 | .068 | 1.42 | 1.73 | W3 | .138 | .148 | 3.51 | 3.76 |
| DD | .808 | .812 | 20.52 | 20.62 | U | .037 | .043 | 0.94 | 1.09 |
| D1 | .720 | ---- | 18.29 | ---- | Y | .956 BSC | | 24.28 BSC | |
| E | .762 | .770 | 19.35 | 19.56 | bb | .497 | .503 | 12.62 | 12.78 |
| E1 | .390 | .394 | 9.91 | 10.01 | c1 | .007 | .011 | 0.18 | 0.28 |
| E2 | .306 | ---- | 7.77 | ---- | e1 | .116 | .124 | 2.95 | 3.15 |
| E3 | .383 | .387 | 9.73 | 9.83 | aaa | .004 | | 0.10 | |
| F | .025 BSC | | 0.64 BSC | | bbb | .006 | | 0.15 | |
| G | .030 BSC | | 0.76 BSC | | ccc | .010 | | 0.25 | |

| | | | |
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PRODUCT DOCUMENTATION, SOFTWARE AND TOOLS

Refer to the following resources to aid your design process.

Application Notes

- AN1907: Solder Reflow Attach Method for High Power RF Devices in Over-Molded Plastic Packages
- AN1955: Thermal Measurement Methodology of RF Power Amplifiers
- AN3789: Clamping of High Power RF Transistors and RFICs in Over-Molded Plastic Packages

Engineering Bulletins

- EB212: Using Data Sheet Impedances for RF LDMOS Devices

Software

- Electromigration MTTF Calculator
- RF High Power Model
- s2p File

Development Tools

- Printed Circuit Boards

To Download Resources Specific to a Given Part Number:

1. Go to <http://www.freescale.com/rf>
2. Search by part number
3. Click part number link
4. Choose the desired resource from the drop down menu

REVISION HISTORY

The following table summarizes revisions to this document.

| Revision | Date | Description |
|----------|-----------|---------------------------------|
| 0 | July 2015 | • Initial Release of Data Sheet |

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